



US00D794816S

(12) **United States Design Patent**
Koyama et al.

(10) **Patent No.:** **US D794,816 S**

(45) **Date of Patent:** **** Aug. 15, 2017**

(54) **SAMPLE HOLDER FOR AN ELECTRON MICROSCOPE**

(71) Applicant: **Hitachi High-Technologies Corporation, Tokyo (JP)**

(72) Inventors: **Kazuhiro Koyama, Tokyo (JP); Masahiro Sasajima, Tokyo (JP)**

(73) Assignee: **HITACHI HIGH-TECHNOLOGIES CORPORATION, Tokyo (JP)**

(**) Term: **14 Years**

(21) Appl. No.: **29/488,729**

(22) Filed: **Apr. 23, 2014**

(30) **Foreign Application Priority Data**

Oct. 24, 2013 (JP) 2013-024760

(51) **LOC (10) Cl.** **24-02**

(52) **U.S. Cl.**
USPC **D24/224**

(58) **Field of Classification Search**
USPC D24/216, 222–225, 227, 231–232;
D10/75, 80, 81; 250/310, 311, 440.11,
250/441.11, 442.11, 443.1; 73/864.91,
73/862.474; 206/557; 228/136;
D16/131, 136
CPC . H01J 37/20; H01J 37/26; H01J 37/28; G02B
21/32; B01L 3/508; G01N 23/04; G01N
23/08; H01R 12/79
See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

3,727,051 A * 4/1973 Page H01J 37/20
250/311
D249,708 S * 9/1978 Smith D24/224

4,262,194 A * 4/1981 Hayward H01J 37/20
250/440.11
D333,187 S * 2/1993 Omi D16/136
5,367,171 A * 11/1994 Aoyama H01J 37/20
250/442.11
5,698,856 A * 12/1997 Frasca H01J 37/20
250/440.11
5,753,924 A * 5/1998 Swann H01J 37/20
250/440.11
D431,300 S * 9/2000 Fisch D24/225
6,246,060 B1 * 6/2001 Ackeret H01J 37/20
250/441.11
6,388,262 B1 * 5/2002 Alani H01J 37/20
250/442.11

(Continued)

Primary Examiner — Ian Simmons

Assistant Examiner — Mark Cavanna

(74) *Attorney, Agent, or Firm* — Baker Botts L.L.P.

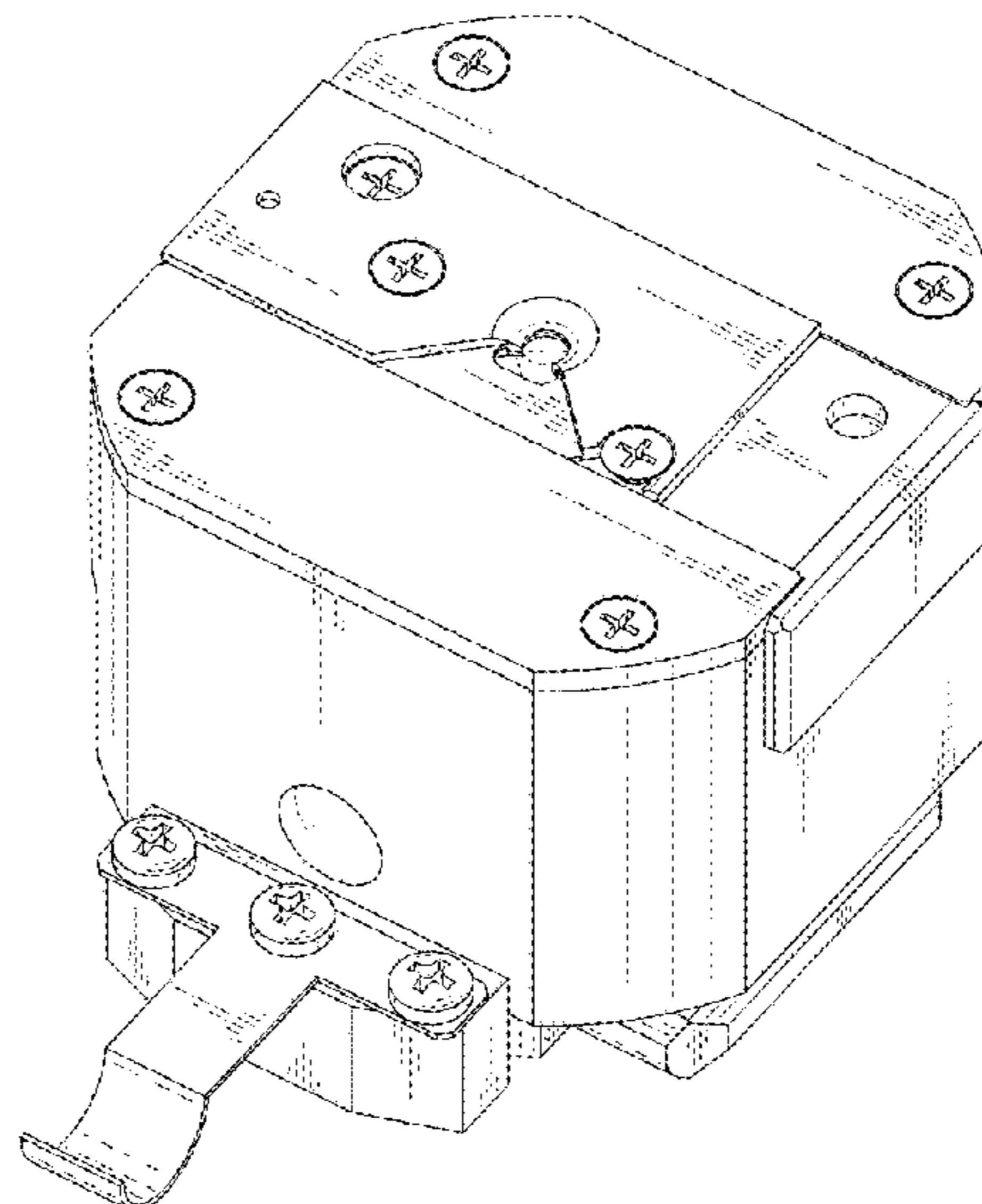
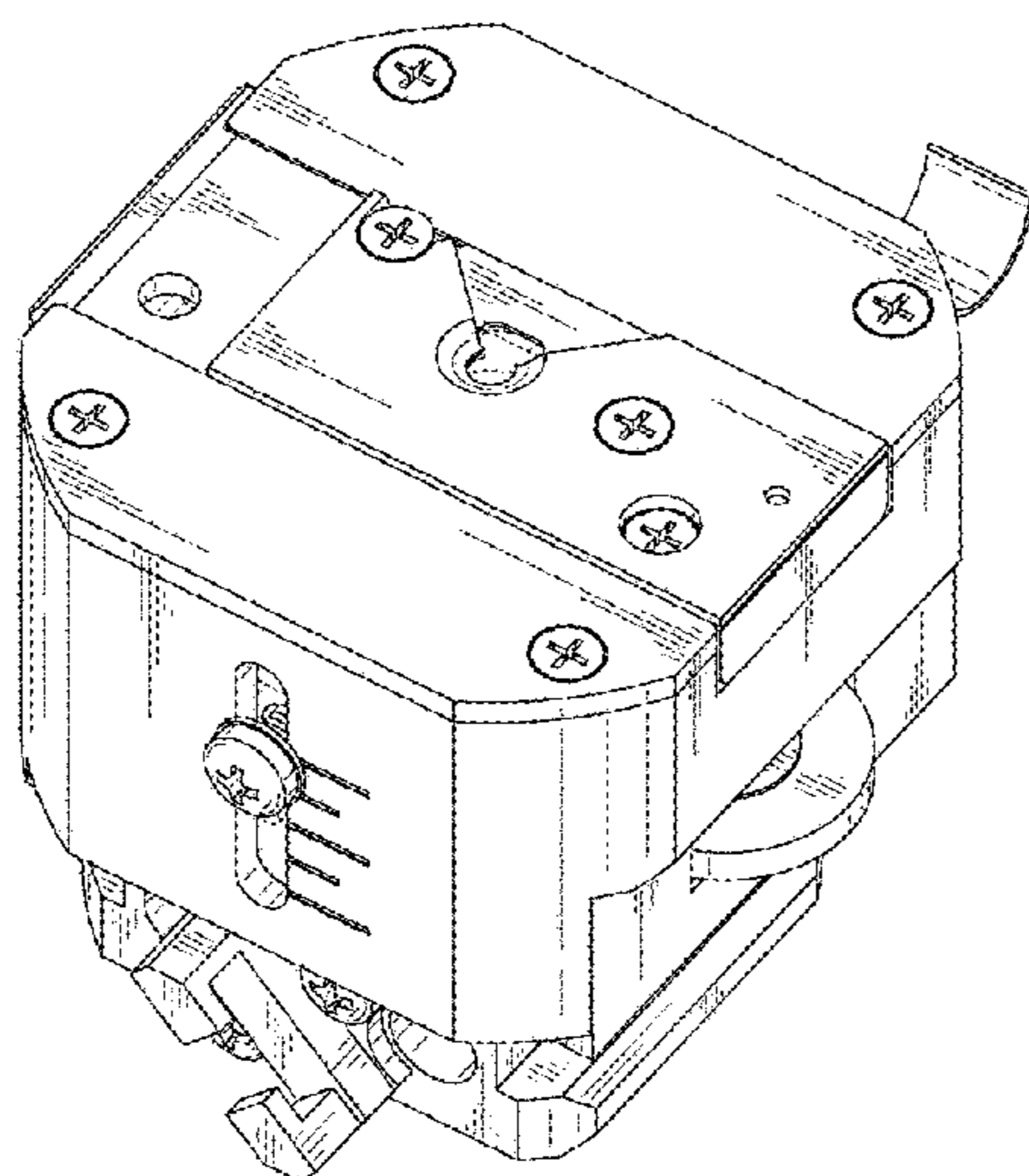
(57) **CLAIM**

We claim the ornamental design for a sample holder for an electron microscope, as shown and described.

DESCRIPTION

FIG. 1 is a front, top and left side perspective view of a sample holder for an electron microscope showing our new design; FIG. 2 is a rear, top and right side perspective view thereof; FIG. 3 is a front elevational view thereof; FIG. 4 is a rear elevational view thereof; FIG. 5 is a left side elevational view thereof; FIG. 6 is a right side elevational view thereof; FIG. 7 is a top plan view thereof; and, FIG. 8 is a bottom plan view thereof. The broken lines are included for the purpose of illustrating unclaimed portions of the sample holder for an electron microscope and form no part of the claimed design.

1 Claim, 8 Drawing Sheets



(56)

References Cited

U.S. PATENT DOCUMENTS

6,414,322 B1 *	7/2002	Carroll	H01J 37/20	250/442.11	8,569,714 B2 *	10/2013	Han	G01N 23/04	250/440.11
6,967,335 B1 *	11/2005	Dyer	G02B 21/32	250/442.11	8,575,566 B2 *	11/2013	Chen	H01J 37/20	250/440.11
6,989,542 B2 *	1/2006	Moses	H01J 37/20	250/311	D700,711 S *	3/2014	Kikuhara	D24/216	
7,230,242 B2 *	6/2007	Behar	B01L 3/508	250/310	D701,782 S *	4/2014	Lekgoathi	D10/81	
D578,653 S *	10/2008	Suzuki	D24/216		8,772,736 B2 *	7/2014	Feng	H01J 37/26	228/136
D578,655 S *	10/2008	Suzuki	D24/224		D711,011 S *	8/2014	Noda	D24/227	
D579,120 S *	10/2008	Suzuki	D24/224		8,835,847 B2 *	9/2014	Yaguchi	H01J 37/20	250/311
7,619,225 B2 *	11/2009	Shan	H01J 37/26	206/557	8,878,144 B2 *	11/2014	Yaguchi	H01J 37/20	250/443.1
7,800,077 B2 *	9/2010	Moriya	H01J 37/20	73/862.474	8,969,828 B2 *	3/2015	Sakamoto	H01J 37/28	250/440.11
D651,226 S *	12/2011	Nagakubo	D16/131		D730,962 S *	6/2015	Ominami	D16/131	
8,143,593 B2 *	3/2012	Milas	H01J 37/20	250/440.11	D731,570 S *	6/2015	Ominami	D16/131	
D660,335 S *	5/2012	Nagakubo	D16/130		9,159,530 B2 *	10/2015	Hosoya	H01J 37/28	
8,338,798 B2 *	12/2012	Terada	H01J 37/20	250/441.11	9,196,457 B2 *	11/2015	Grogan	H01J 37/20	
D684,274 S *	6/2013	Hosoya	D24/224		D748,706 S *	2/2016	Ominami	D16/131	
8,497,487 B2 *	7/2013	Milas	H01J 37/20	250/440.11	9,343,261 B2 *	5/2016	Chang	H01J 37/26	
D692,578 S *	10/2013	Kikuhara	D24/216		9,437,393 B2 *	9/2016	Damiano, Jr.	H01R 12/79	
						2002/0194938 A1 *	12/2002	Koo	H01J 37/20	73/864.91
						2005/0035302 A1 *	2/2005	Morrison	H01J 37/20	250/442.11
						2007/0125947 A1 *	6/2007	Sprinzak	B01L 3/508	250/310

* cited by examiner

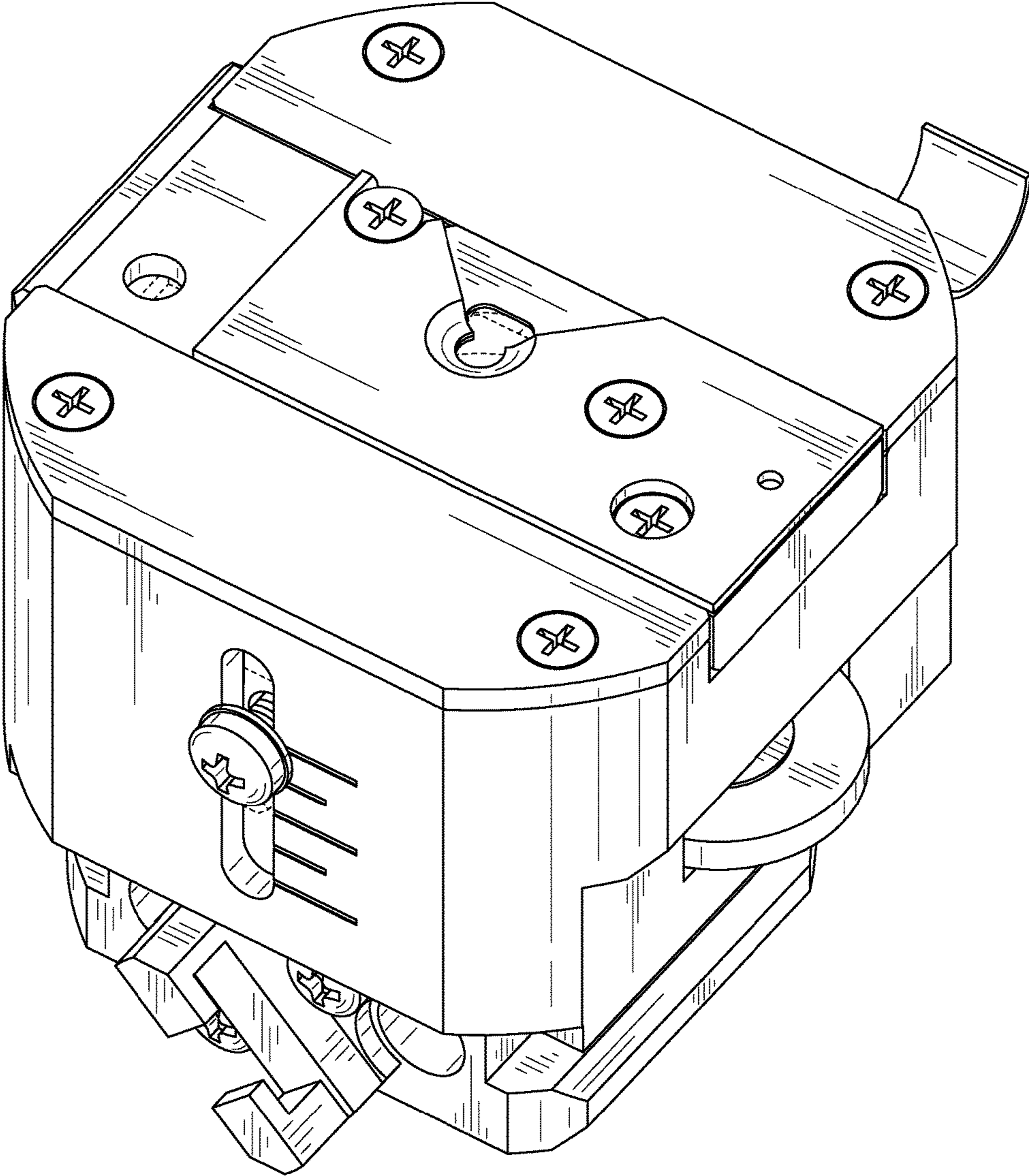


FIG. 1

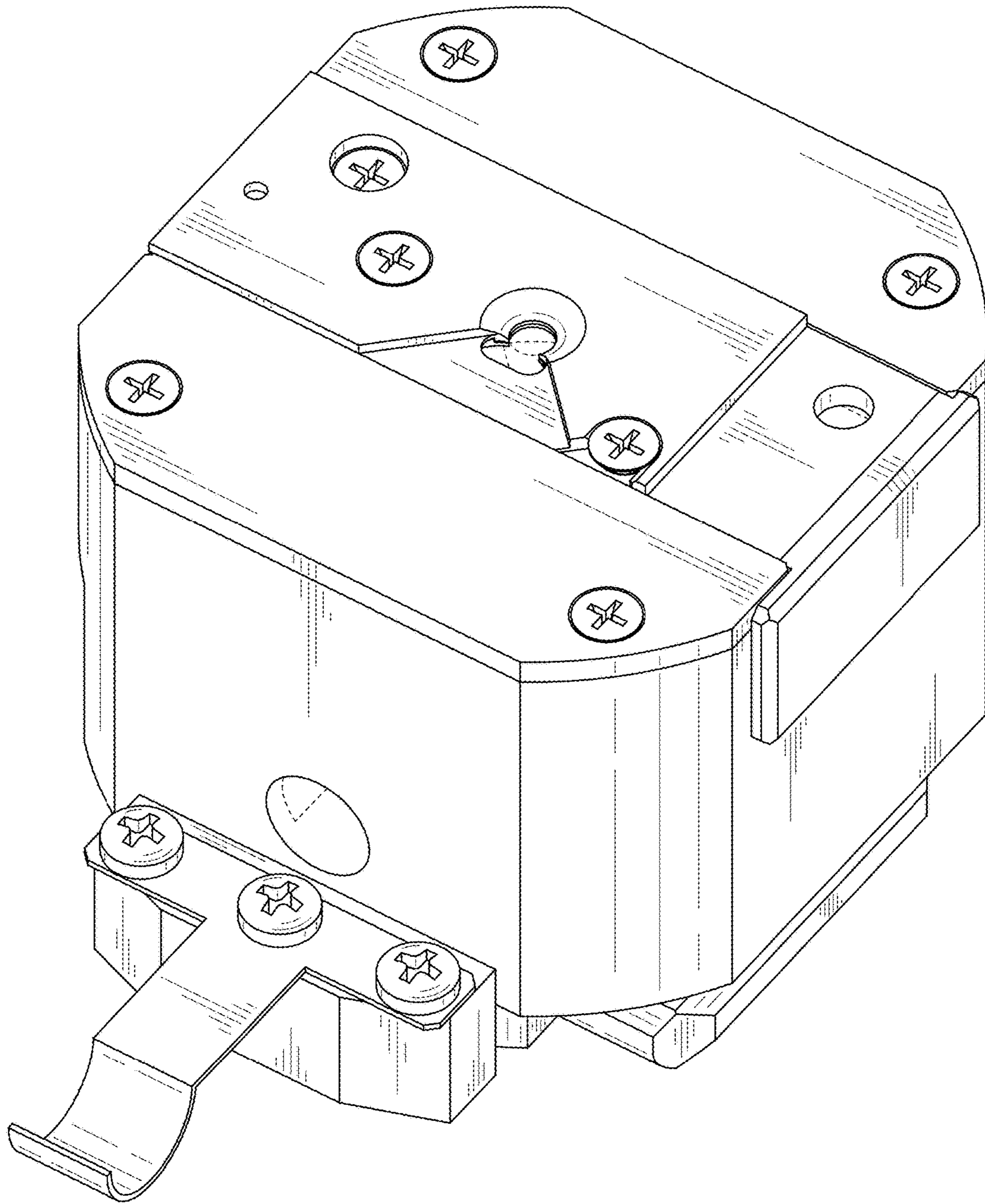


FIG. 2

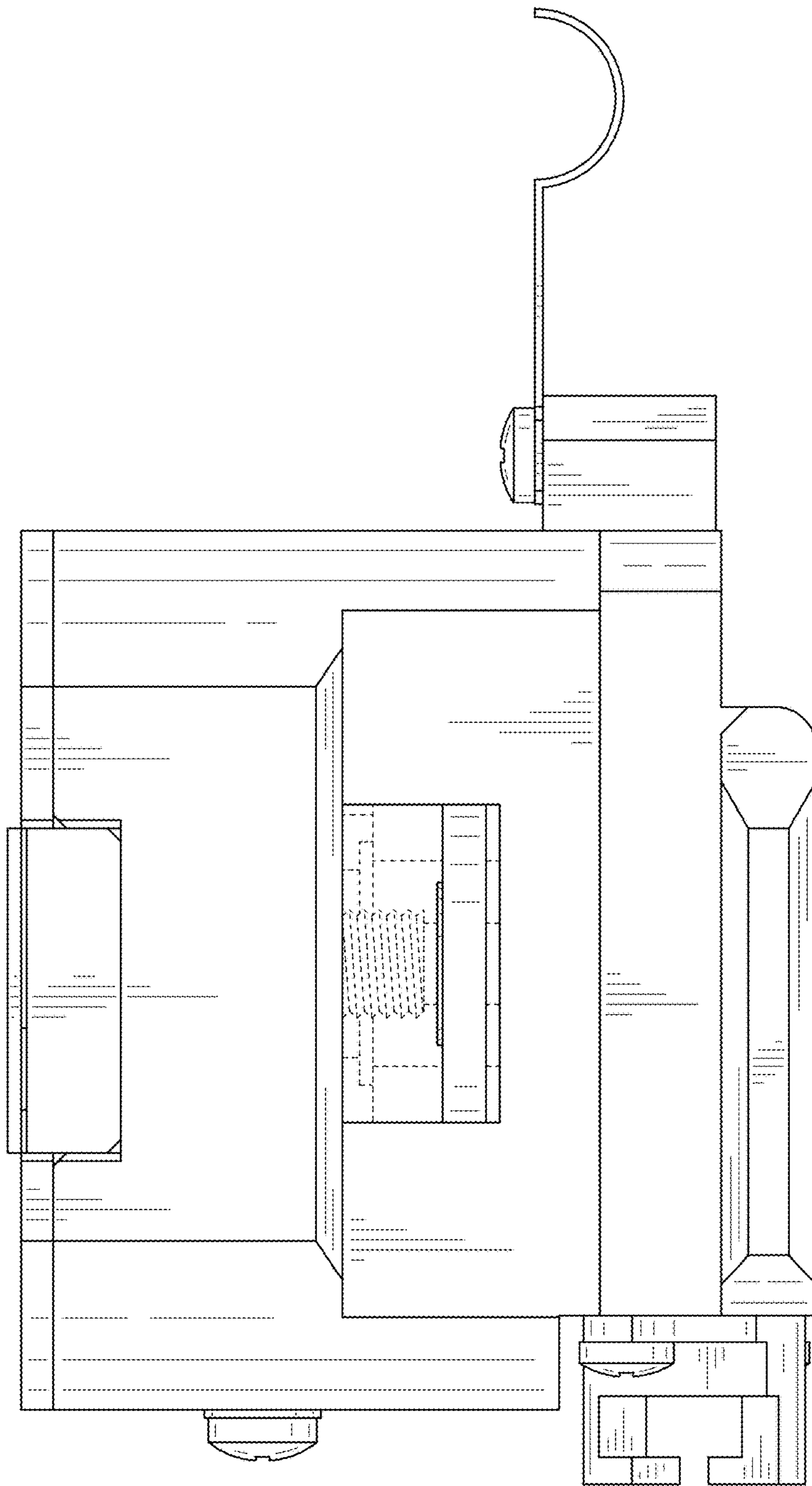


FIG. 3

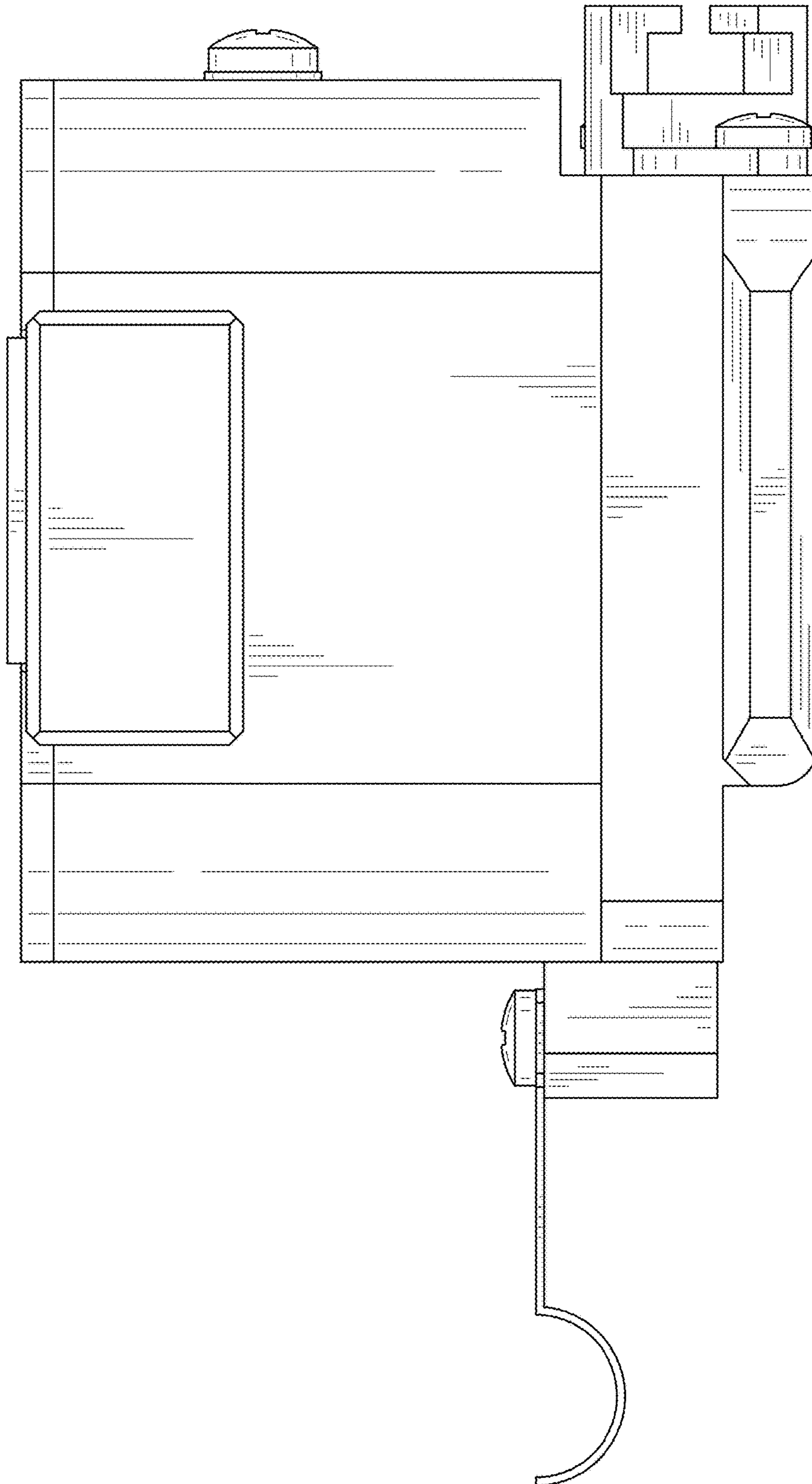


FIG. 4

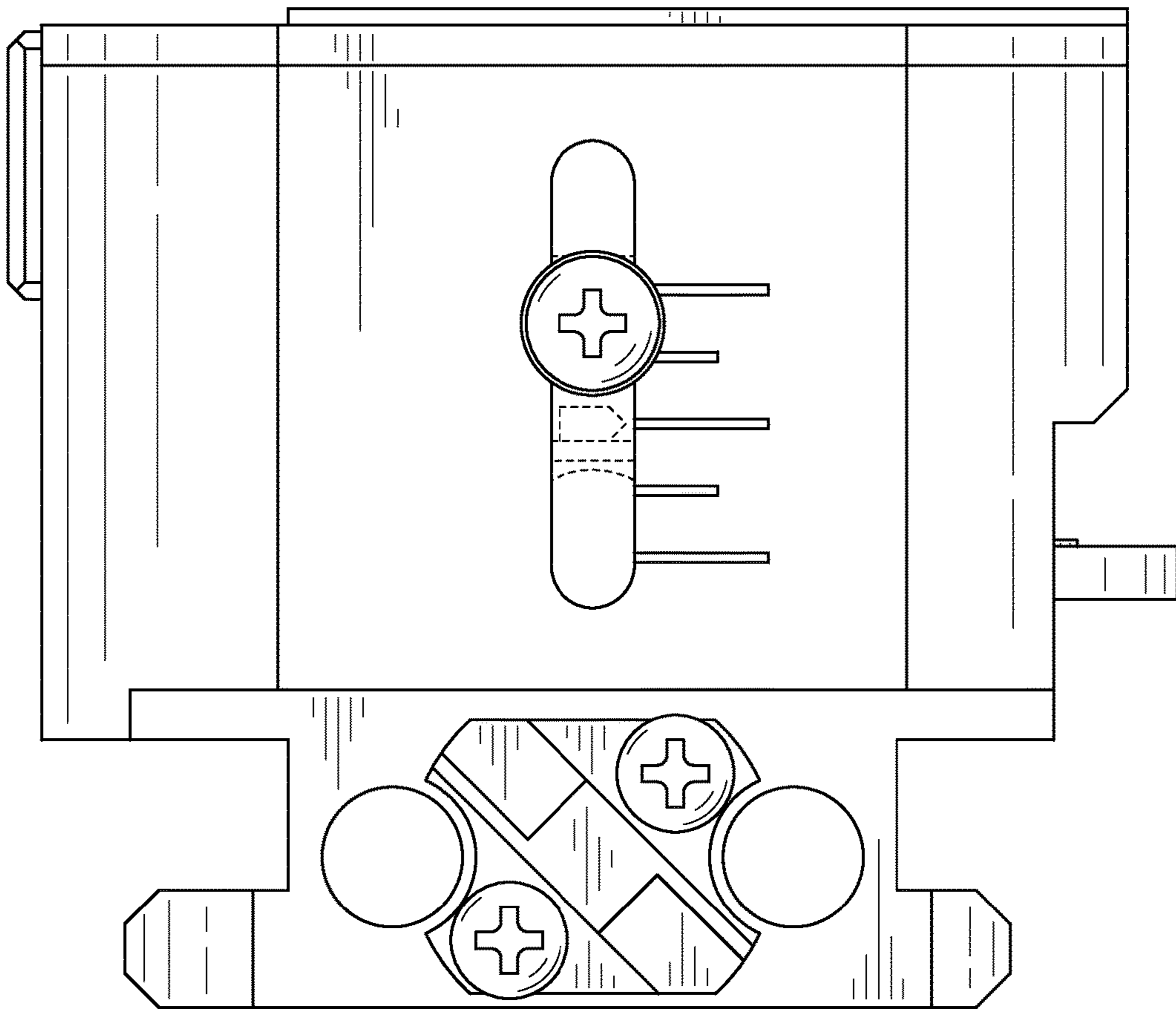


FIG. 5

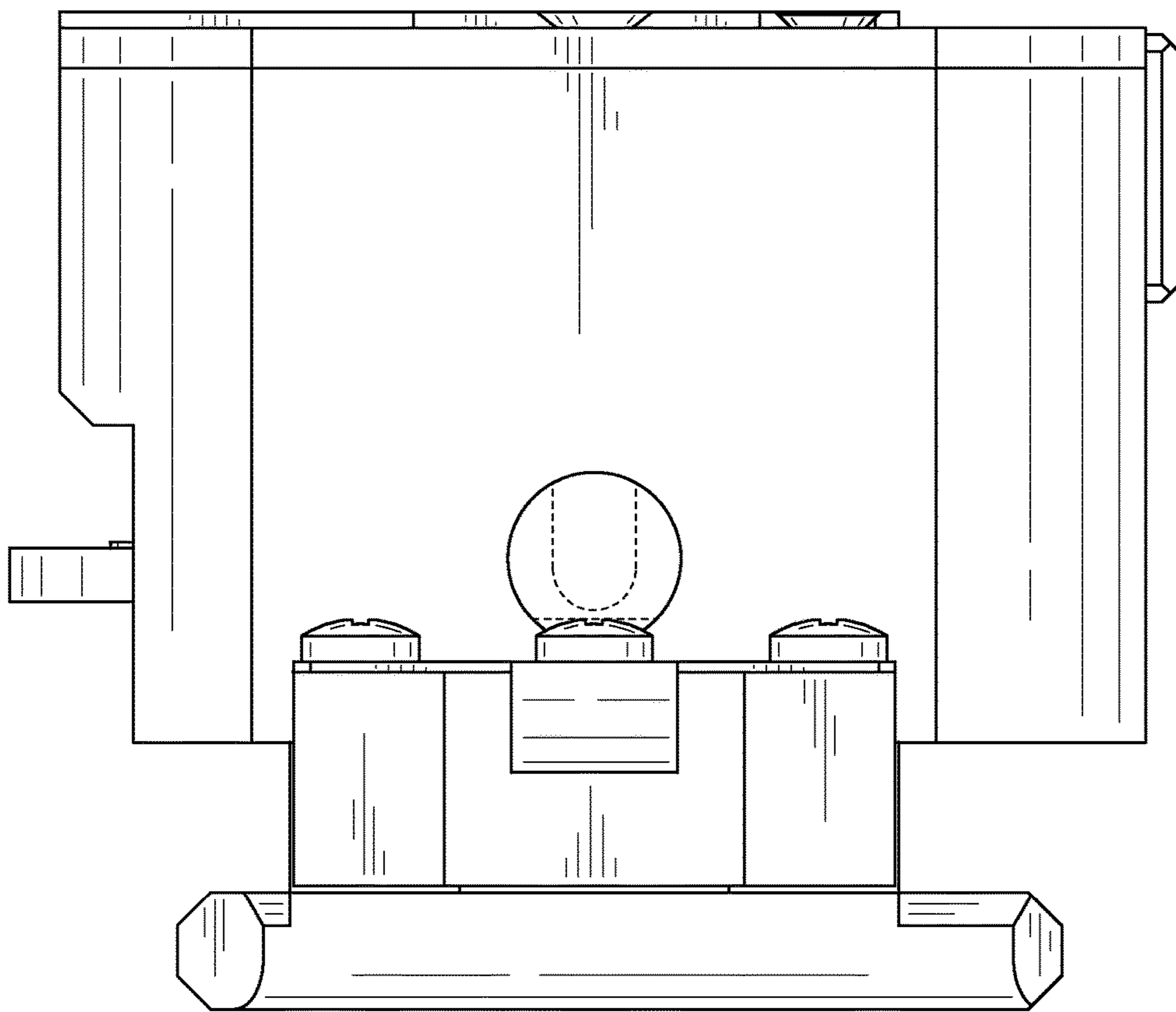


FIG. 6

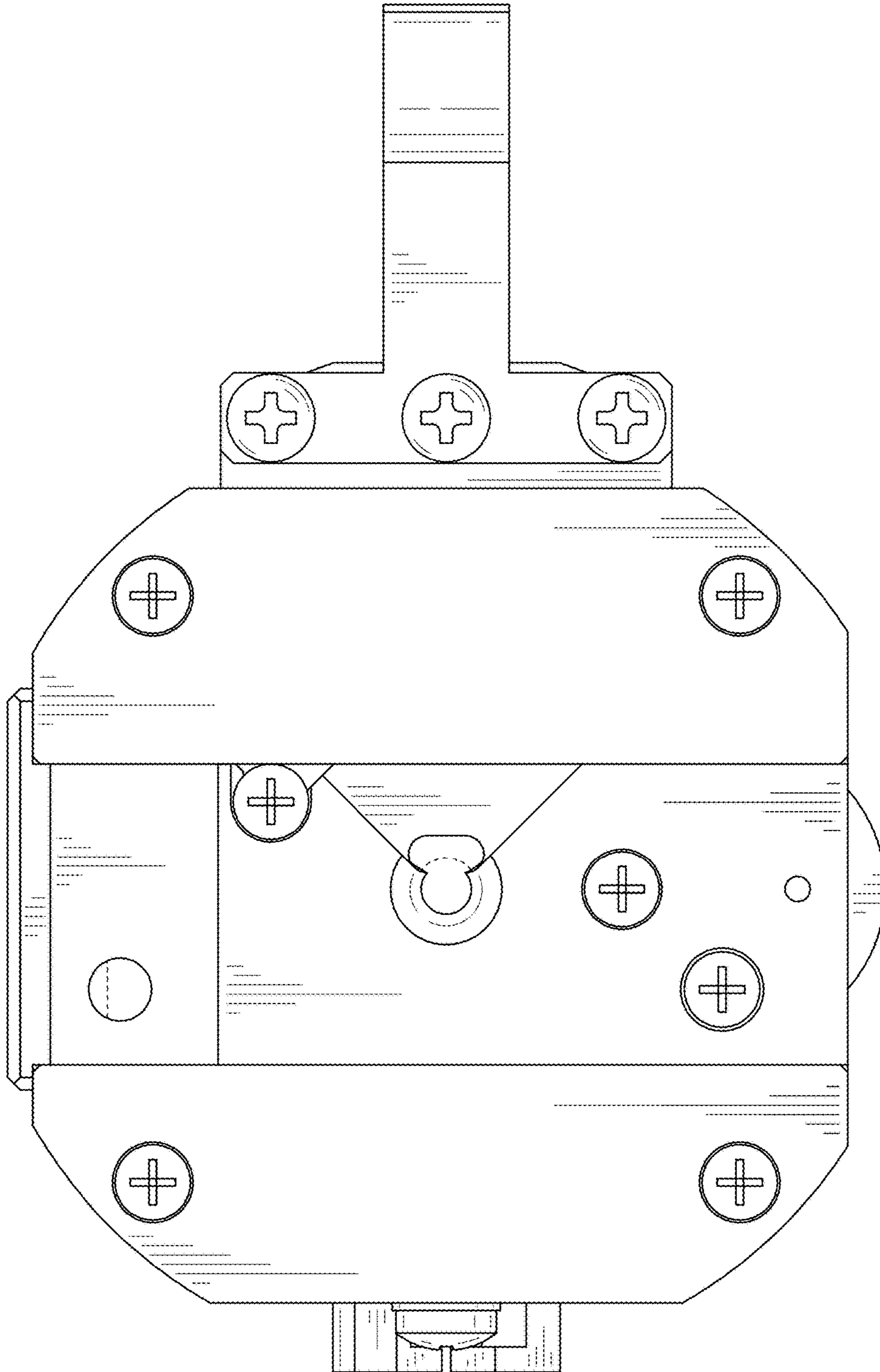


FIG. 7

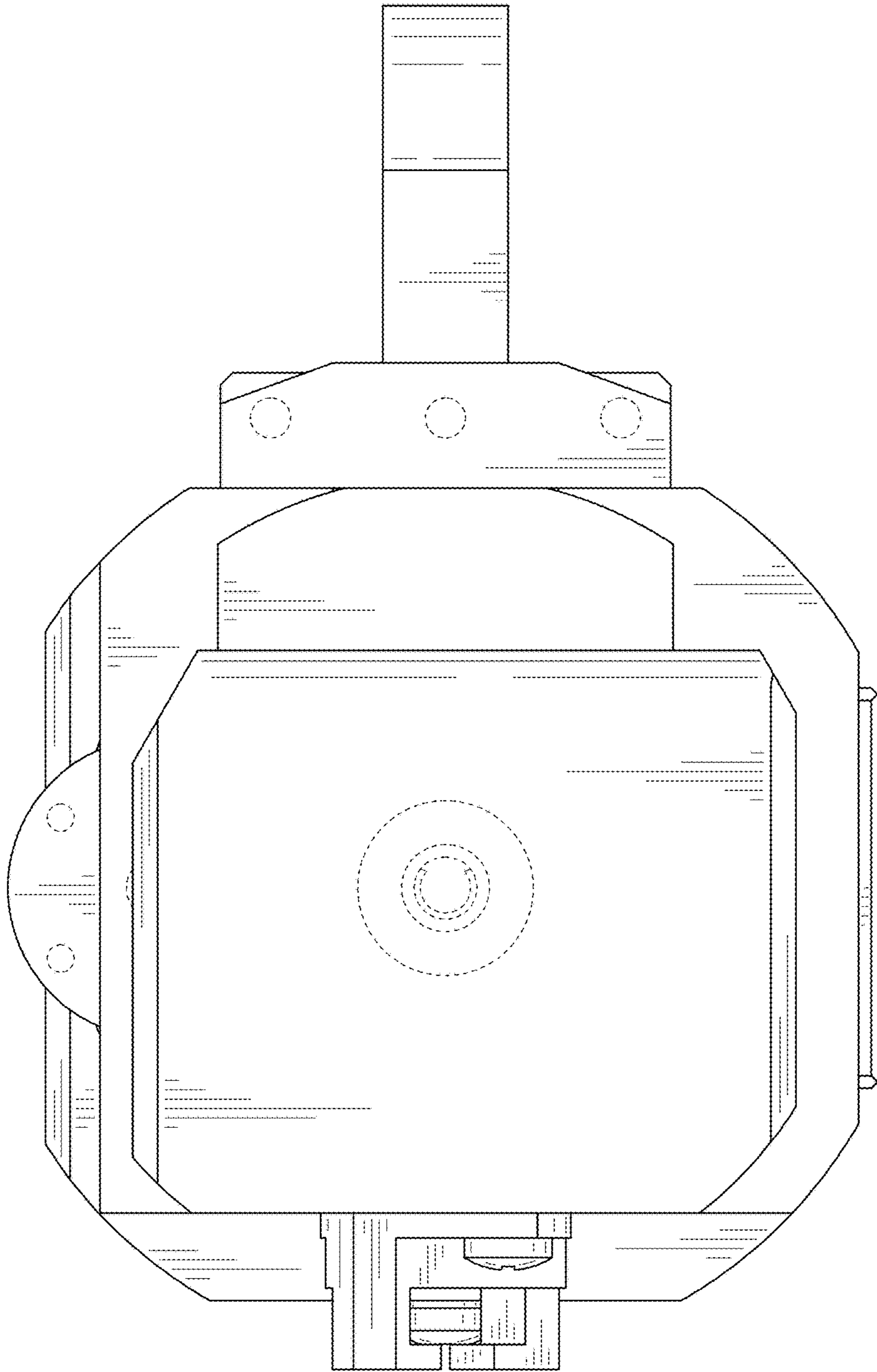


FIG. 8